Special Issue

Advanced Studies in Optical Imaging and Sensing

Message from the Guest Editors

Optical imaging and sensing technologies constitute fundamental tools for the development of many fields. Laser and microwave radar technologies have received extensive attention due to their advantages in achieving high-resolution detection and imaging. In this Special Issue, we are interested in publishing original articles and reviews that discuss Laser radar and microwave radar and key technologies. We welcome relevant contributions on issues including, but not limited to:

- Three-dimensional Lidar scene perception and reconstruction;
- Laser coherence detection and imaging;
- Target detection and recognition;
- Laser radar 3D point cloud imaging.

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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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